

Tool Slot #1	Tool Slot #1	Tool Slot #1	Tool Slot #1	Tool Slot #50	Tool Slot #50	Tool Slot #50	Tool Slot #50
Cassette Sl#	Pre Scan	Post Scan	Adders	Cassette Sl#	Pre Scan	Post Scan	Adders
Slot 1	80	135	55	Slot 50	70	23	-47
Slot 1	72	390	288	Slot 50	61	114	53
Slot 1	75	260	195	Slot 50	136	203	67
Slot 1	90	298	208	Slot 50	76	106	30
Slot 1	134	206	72	Slot 50	148	179	31
Slot 1	84	223	139	Slot 50	143	166	23
Slot 1	83	195	112	Slot 50	148	162	14
Slot 1	113	1087	974	Slot 50	101	1002	900
Slot 1	124	428	304	Slot 50	124	274	150
Slot 1	152	1215	1063	Slot 50	116	209	93

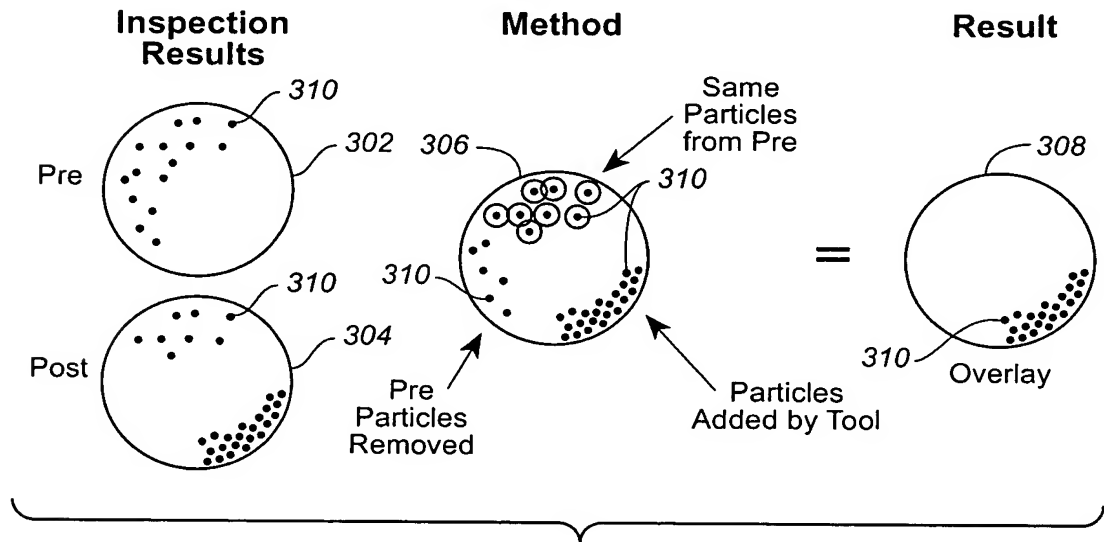
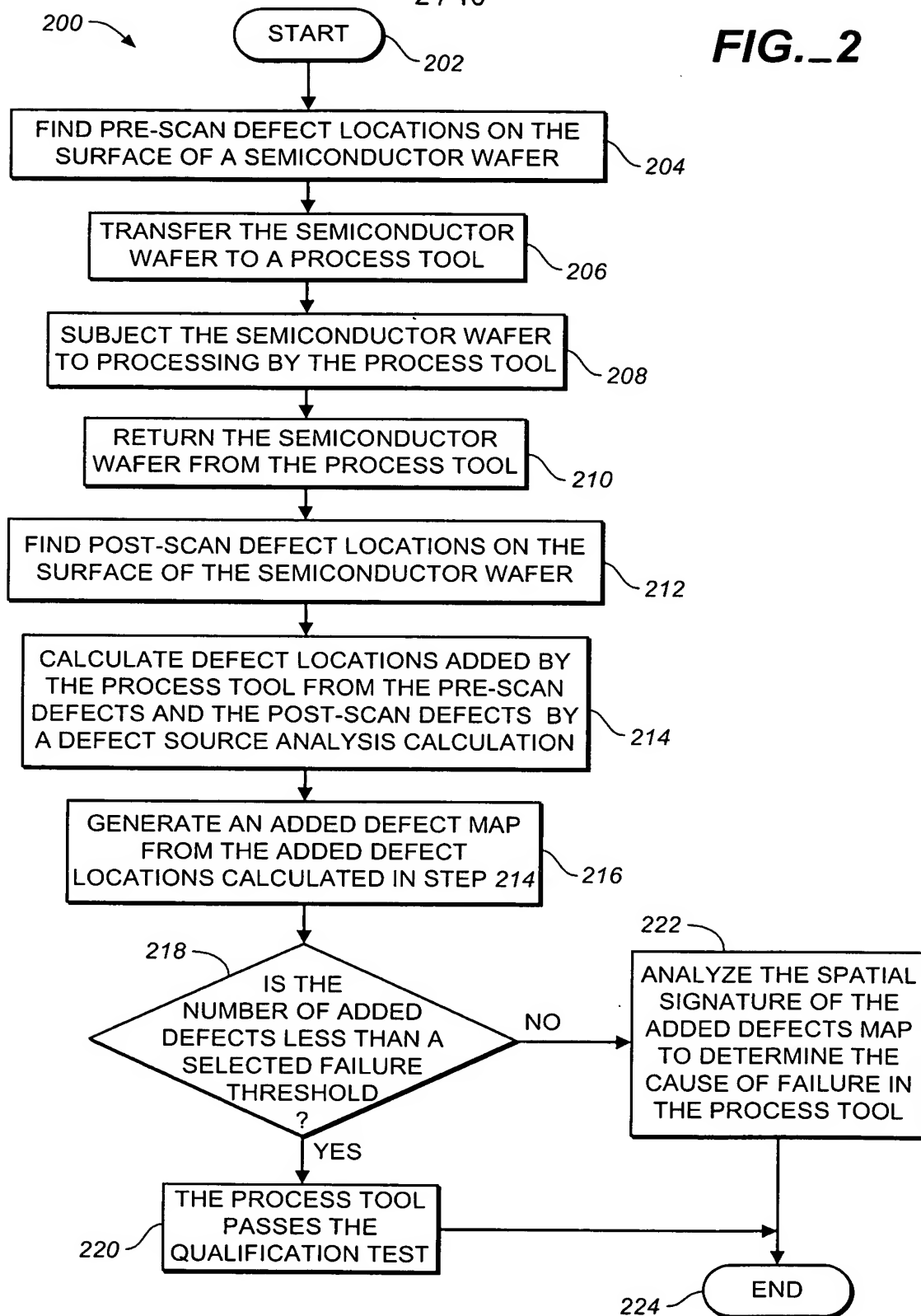
FIG._1**FIG._3**

FIG. 2



400

START

402

FIG. 4A

SORT THE DEFECT LOCATIONS ON THE PRE-TEST WAFER AND THE POST-TEST WAFER IN ORDER ACCORDING TO THE VALUE OF THE X-COORDINATE AND THE Y-COORDINATE

404

SELECT THE FIRST DEFECT LOCATION IN THE FIRST ORDERED LIST OF DEFECT LOCATIONS AS A FIRST POINT

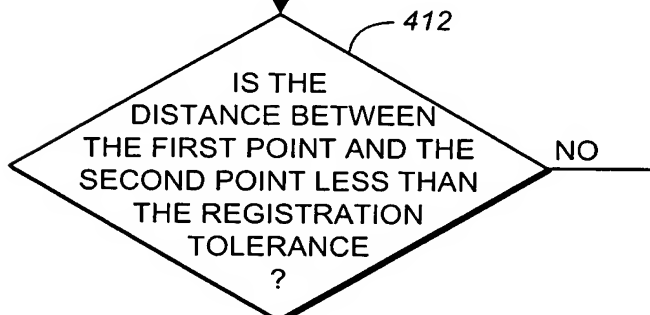
406

SELECT THE FIRST DEFECT LOCATION IN THE SECOND ORDERED LIST OF DEFECT LOCATIONS AS A SECOND POINT

408

CALCULATE THE COORDINATE DISTANCE BETWEEN THE FIRST POINT AND THE SECOND POINT

410



MARK THE DEFECT LOCATION IN THE POST-WAFER MAP CORRESPONDING TO THE SECOND POINT AS A NON-ADDER

414

A

C

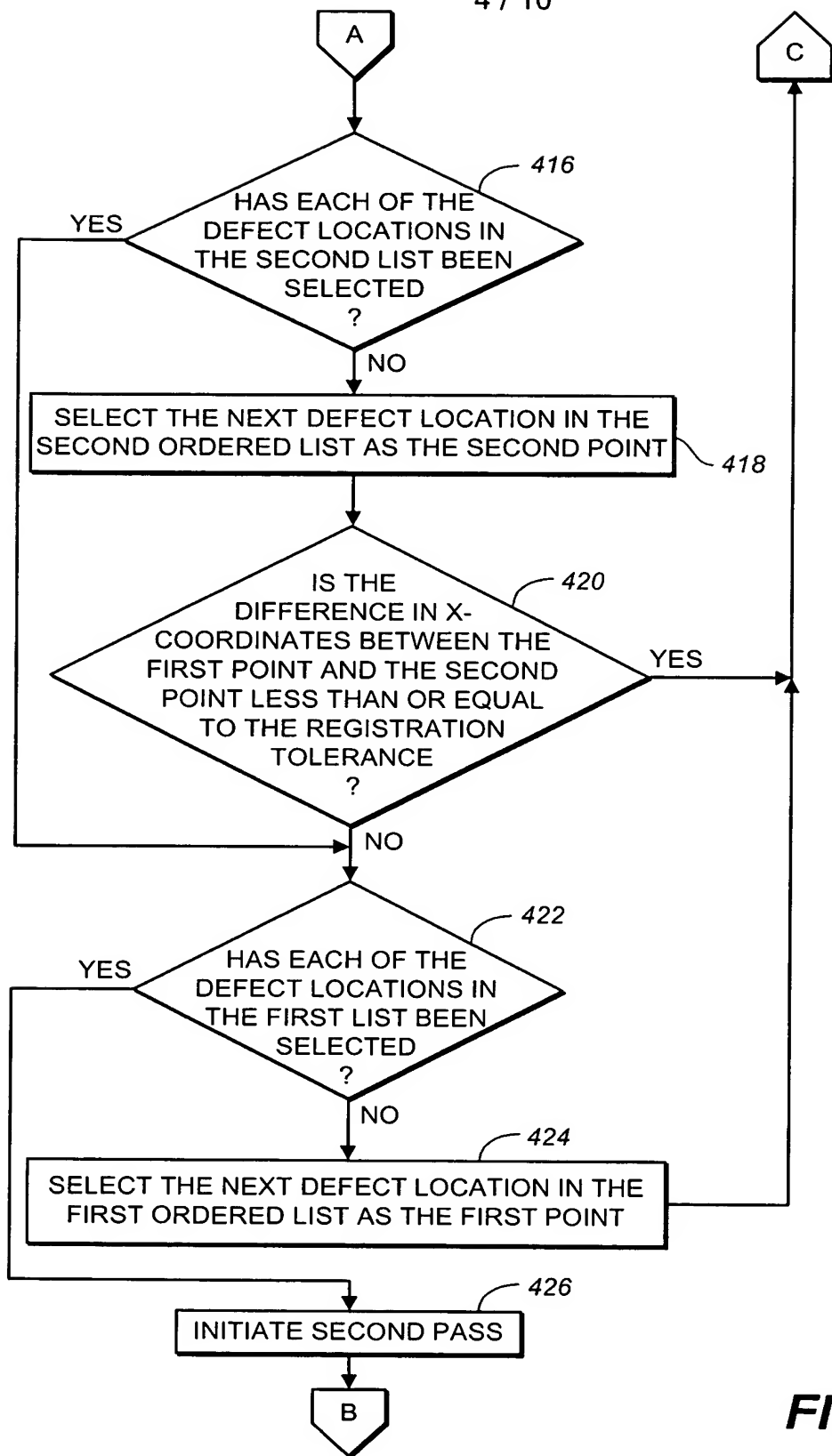
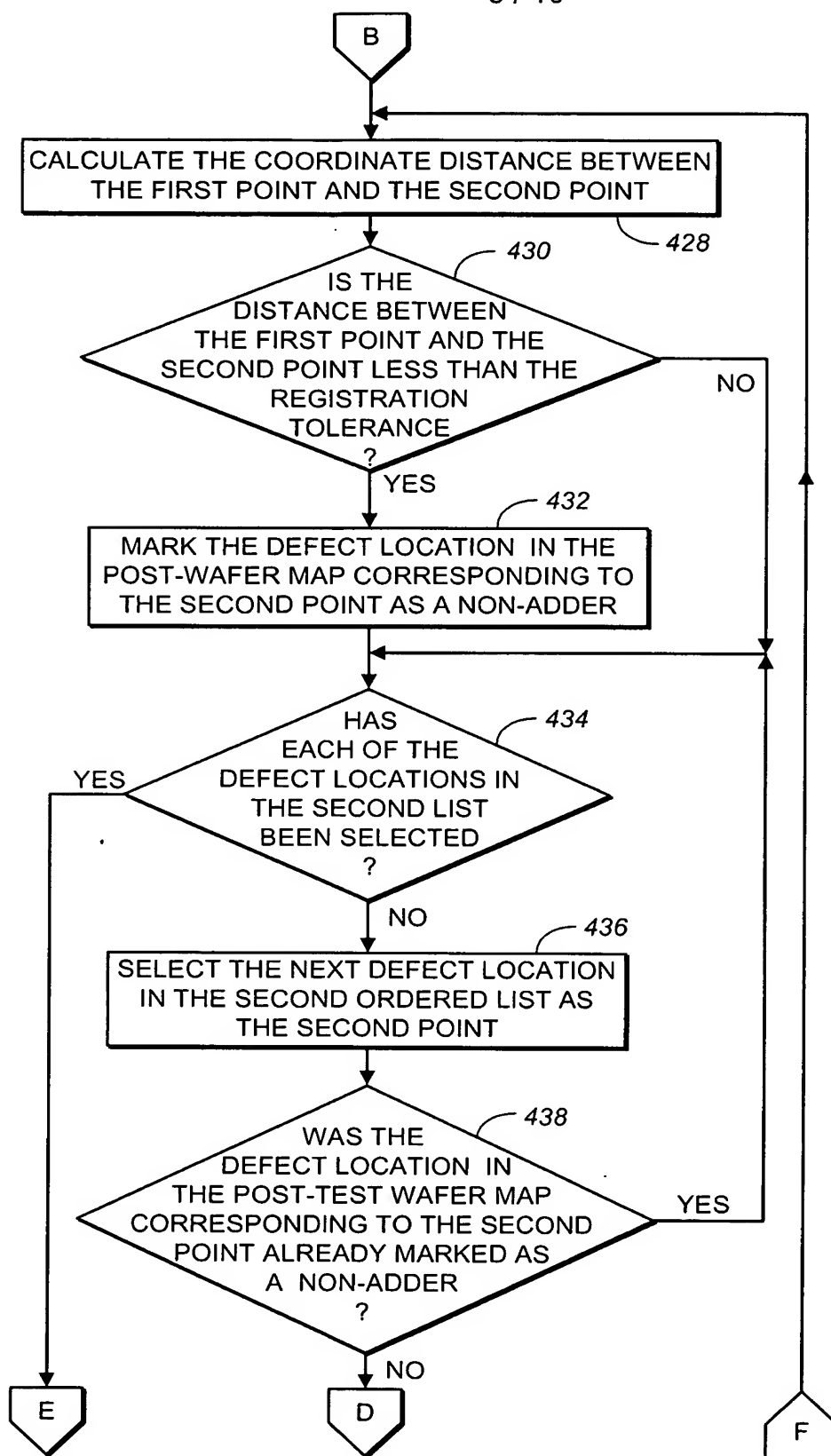
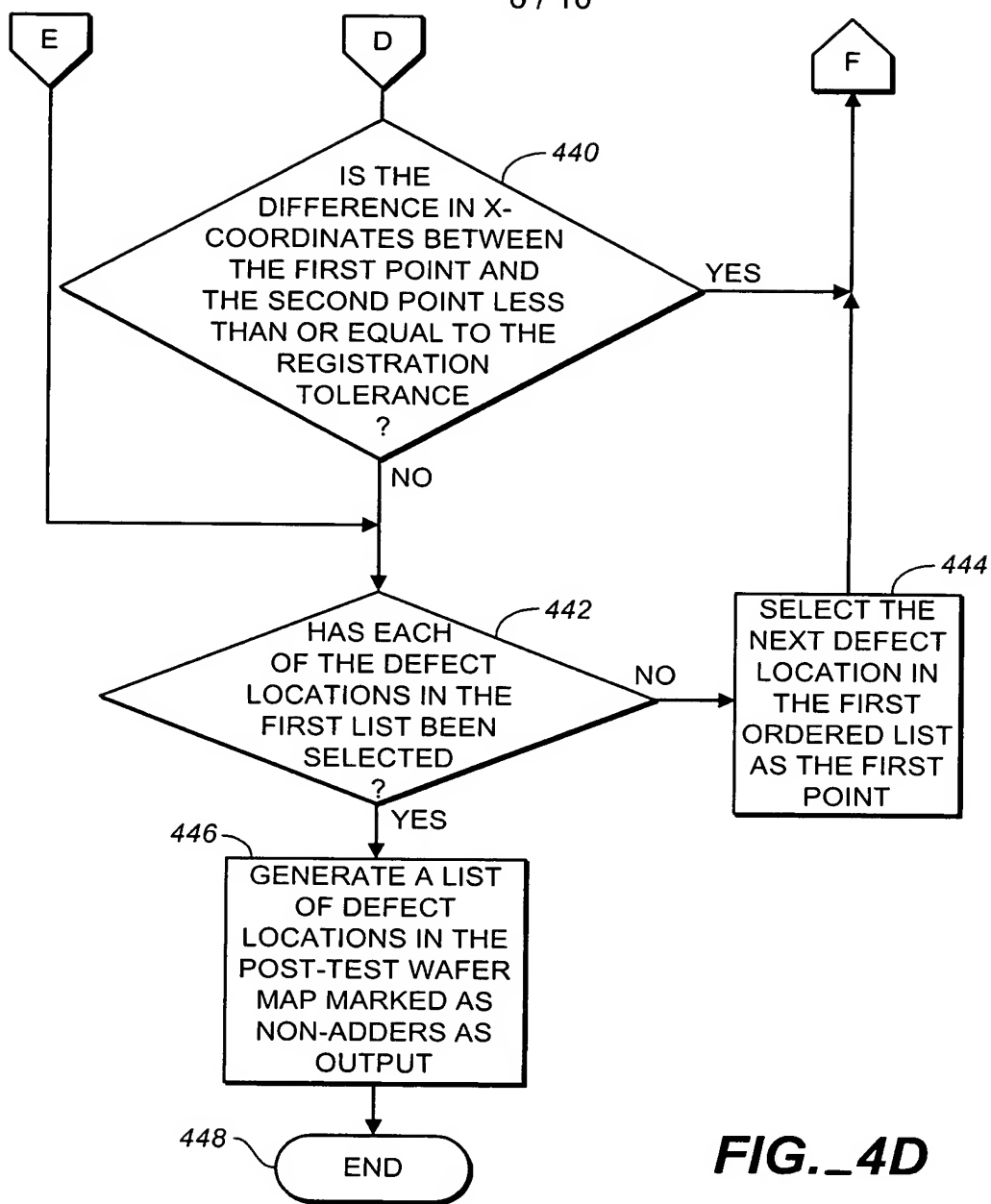


FIG._4B

FIG. 4C



**FIG._4D**

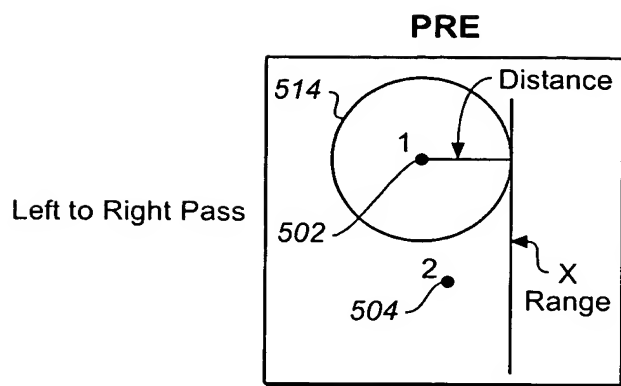


FIG._5A

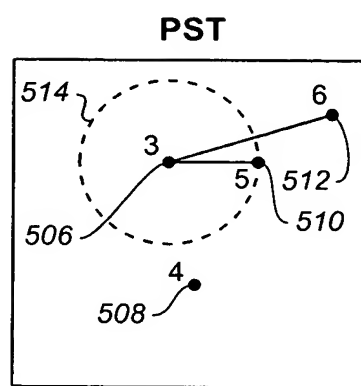


FIG._5B

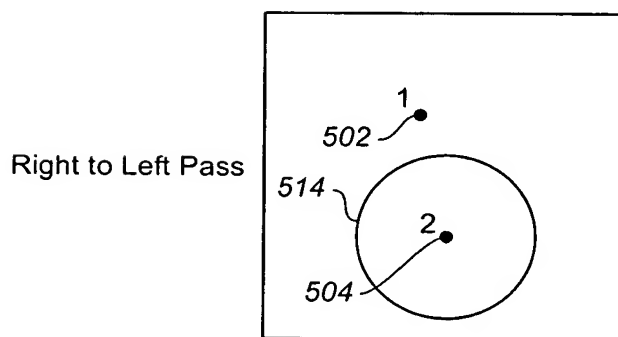


FIG._6A

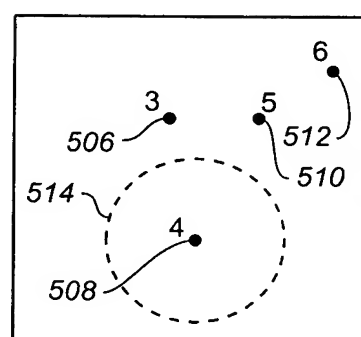


FIG._6B

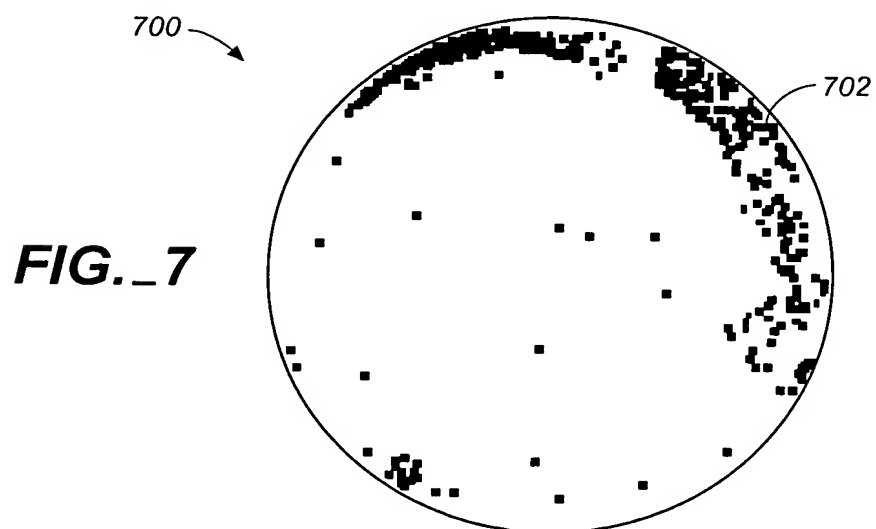
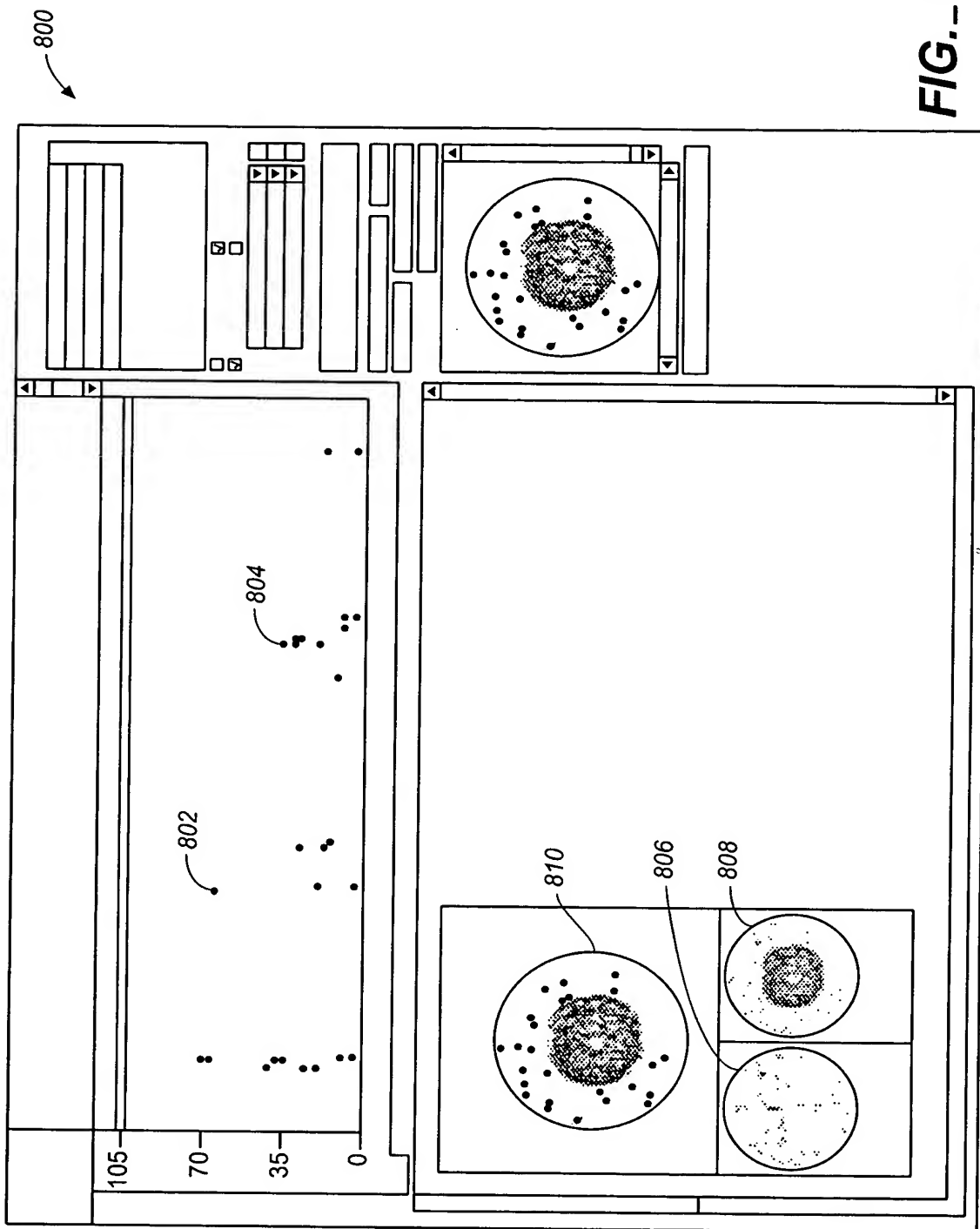


FIG. 8



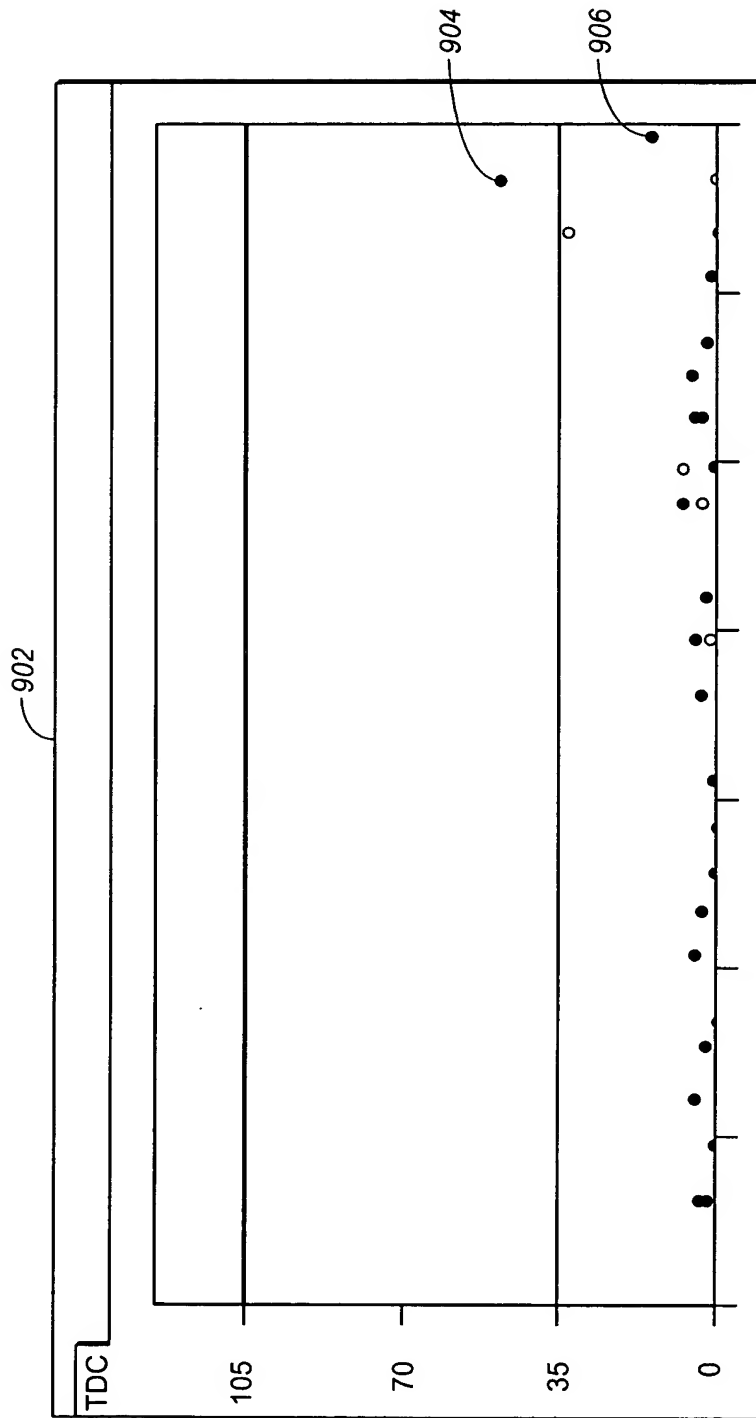


FIG. 9A

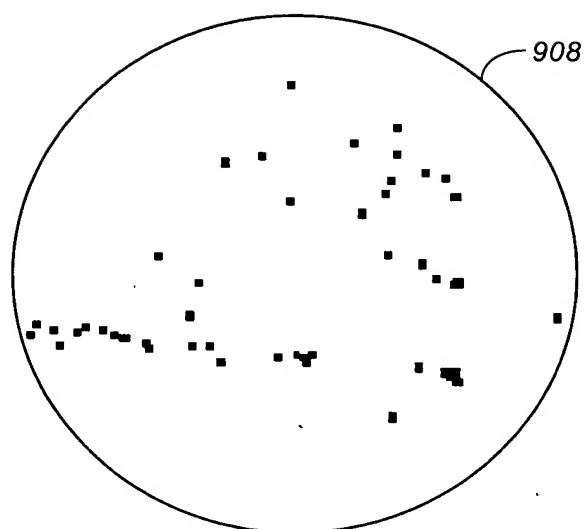


FIG._9B

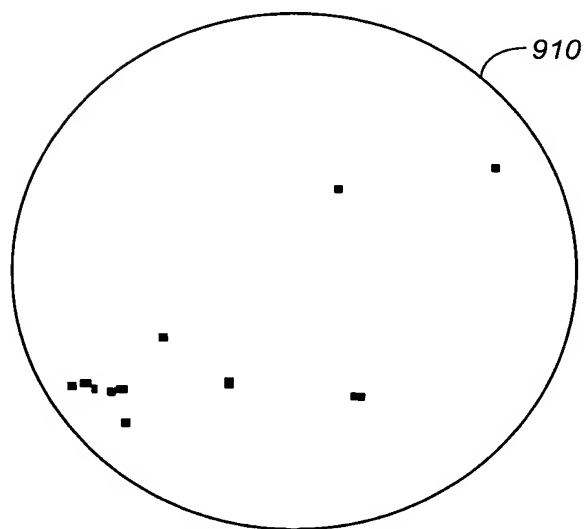


FIG._9C